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Inventor: **Denise M. Eppich et al.**

Title: **Methods of Forming Transistor Devices and Capacitor Constructions**

Assignee: **Micron Technology, Inc.**

Serial No.: **10/757,253**

Filed: **January 13, 2004 [RCE Filed Herewith]**

**INFORMATION DISCLOSURE STATEMENT**

**PURSUANT TO 37 C.F.R. §§ 1.56, 1.97 AND 1.98**

The attached Form PTO-1449 is submitted in compliance with 37 CFR §1.56. Pursuant to FEDERAL REGISTER, Vol. 69, No. 182, pg. 56542 (September 21, 2004), no copies of any cited U.S. patents or U.S. published applications are included herewith. No admission is made regarding whether the listed references are prior art.

Citation of these references is respectfully requested.

Dated: \_\_\_\_\_

5/4/06

Respectfully submitted,

By: \_\_\_\_\_

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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-2467		SERIAL NO. 10/757,253	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				<div style="border: 2px solid black; border-radius: 50%; padding: 10px; display: inline-block;"> <b>OFFICE</b>  <b>MAY 04 2006</b>  <b>PATENT &amp; TRADEMARK OFFICE</b> </div>			
				APPLICANT Denise M. Eppich et al.		FILING DATE Jan. 13, 2004 [RCE filed herewith]	
						GROUP 2823	
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
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FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
	AM						
	AN						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AO						
	AP						
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<p>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>							